



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Glenn J. Leedy

Application No. : 10/672,961 Confirmation No.: 9439

Filed : September 26, 2003

For : THREE DIMENSIONAL MULTI LAYER MEMORY AND  
CONTROL LOGIC INTEGRATED CIRCUIT  
STRUCTURE

Group Art Unit : 2822

Examiner : Monica Lewis

Mail Stop AMENDMENT  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, Virginia 22313-1450

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Sir:

In accordance with 37 C.F.R. §§ 1.56 and 1.97, applicant wishes to call the attention of the Examiner to the following documents:

Foreign Patent Documents

DE 3233195	03/17/1983	Mitsubishi Electric Corporation
JP 2037655	02/07/1990	Siemens AG
JP 3127816	05/30/1991	Canon KK
JP 3174715	07/29/1991	Fujitsu Limited
WO 98/19337	05/07/1998	Trusi Technologies, LLC

Nonpatent Literature Documents

Wolf, Stanley and Richard N. Tauber; Silicon  
Processing For the VLSI Era, Volume 1: Process  
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1986, pages 191-194

05/01/2007 AWONDAF1 00000036 061075 10672961

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Allen, Mark G.,: Senturia, Stephen D.;  
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pp. 352-356.

Kochugova, I.V.; Nikolaeva, L.V.; Vakser, N.M.,  
(M.I. Kalinin Leningrad Polytechnic Institute  
(USSR); "Electrophysical investigation of thin-  
layered inorganic coatings"; 1989; pp. 826-828.

The aforementioned references are listed on the  
accompanying Form PTO/SB/08 (submitted in duplicate). Pursuant to  
37 C.F.R. 1.98 (a)(2), copies of the aforementioned Foreign Patent  
Documents and Non-Patent Literature Documents are enclosed  
herewith.

Applicant reserves the right to establish the  
patentability of the claimed invention over any of the information  
provided herewith, and/or to prove that this information may not  
be prior art, and/or to prove that this information may not be  
enabling for the teachings purportedly offered.

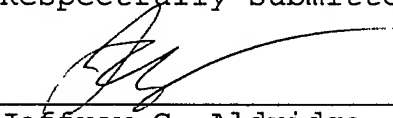
The above-identified documents were previously cited in an Information Disclosure Statement filed on September 26, 2006, and were not considered by the Examiner. These references are being re-submitted herewith for the Examiner's consideration.

It is respectfully requested that these references be: (1) fully considered by the Patent and Trademark Office during the examination of this application; and (2) printed on any patent which may issue on this application. Applicant requests that a copy of Form PTO-SB/08, as considered and initialed by the Examiner, be returned with the next communication.

This Statement is submitted with a Request for Continued Examination under 37 C.F.R. § 1.114. The Director is hereby authorized to charge \$180.00 in payment of the fee for submission of this Information Disclosure Statement pursuant to 37 C.F.R. §1.97(c)(2), payment of any additional fees required in connection with this Statement, or to credit any overpayment of the same, to Deposit Account No. 06-1075 (Order No.: 001202-0127). A duplicate copy of this Information Disclosure Statement is enclosed herewith.

An early and favorable action is respectfully requested.

Respectfully submitted,



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PTO/SB/08a/b (08-03)

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Substitute for form 1449A/B/PTO				<b>Complete if Known</b>	
<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>  (Use as many sheets as necessary)				Application Number	10/672,961 (Conf. No. 9439)
				Filing Date	September 26, 2003
				First Named Inventor	Glenn J. Leedy
				Art Unit	2822
				Examiner Name	Monica Lewis
Sheet	1	of	1	Attorney Docket Number	ELM-2 CONT. 4

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. <sup>1</sup>	Document Number Number-Kind Code <sup>2</sup> (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear

FOREIGN PATENT DOCUMENTS						
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		WO 98/19337	05-07-1998	Trusi Technologies, LLC		

NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T <sup>2</sup>
		Wolf, Stanley and Richard N. Tauber; Silicon Processing For the VLSI Era, Volume 1: Process Technology; Sunset Beach, CA: Lattice Press, 1986, pages 191-194	
		European Search Report for Application No. EP 02 00 9643 (date completed: October 8, 2002)	
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EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. <sup>1</sup> Applicant's unique citation designation number (optional). <sup>2</sup> See Kinds Codes of USPTO Patent Documents at [www.uspto.gov](http://www.uspto.gov) or MPEP 901.04. <sup>3</sup> Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). <sup>4</sup> For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. <sup>5</sup> Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. <sup>6</sup> Applicant is to place a check mark here if English language Translation is attached.

Examiner Signature		Date Considered	
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 Patent and Trademark Office; U.S. DEPARTMENT OF COMMERCE

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